© 1992 American Statistical Association and
the American Society for Quality Control

TECHNOMETRICS, NOVEMBER 1992, VOL. 34, NO. 4

TECHNOMETRICS

CONTENTS OF VOLUME 34
NUMBERS 133–136

Articles 1, 127, 251, 377
Book Reviews 97, 223, 353, 485
Corrections 372, 501
Editorial Collaborators 503

Index to Volume 34
Articles, by Author 505
Books Reviewed, by Author 506
Book Reviewers 509

INDEX TO VOLUME 34 (1992)

ARTICLES, BY AUTHOR

Best, D. J., and Rayner, J. C. W., Letter to the Editor, 250
Box, George, and Kramer, Tim, "Statistical Process Monitoring and Feedback Adjustment—A Discussion," 251; Response, 282
Buck, Robert J. (*see* Welch, William J.)
Carrillo-Gamboa, Olivia, and Gunst, Richard F., "Measurement-Error-Model Collinearities," 454
Carroll, R. J., and Spiegelman, C. H., "Diagnostics for Nonlinearity and Heteroscedasticity in Errors-in-Variables Regression," 106
Champ, Charles W. (*see* Lowry, Cynthia A.)
Chen, Youyi (*see* Wu, C. F. J.)
Christensen, Ronald, Pearson, Larry M., and Johnson, Wesley, "Case-Deletion Diagnostics for Mixed Models," 38
Crawford, Sybil L., DeGroot, Morris H., Kadane, Joseph B., and Small, Mitchell J., "Modeling Lake-Chemistry Distributions: Approximate Bayesian Methods for Estimating a Finite-Mixture Model," 441
Crowder, Stephen V., "An SPC Model for Short Production Runs: Minimizing Expected Cost," 64
David, H. T. (*see* Jobe, J. Marcus)
DeGroot, Morris H. (*see* Crawford, Sybil L.)
Doganaksoy, Necip (*see* Vander Wiel, Scott A.)
Doksum, Kjell A., and Hóyland, Arnljot, "Models for Variable-Stress Accelerated Life Testing Experiments Based on Wiener Processes and the Inverse Gaussian Distribution," 74
Draper, Norman R. (*see* Lin, Dennis K. J.)
Faltin, Frederick, W. (*see* Vander Wiel, Scott A.)
Farebrother, R. W., Letter to the Editor, 375
Fung, K. Y. (*see* Paul, S. R.)
Garcia, Carlos E. (*see* Wardrop, Daniel M.)
Goldberg, Kenneth M.,and Iglewicz, Boris, "Bivariate Extensions of the Boxplot," 307
Greenberg, Betsy S., and Stokes, S. Lynne, "Estimating Nonconformance Rates After Zero-Defect Sampling With Rectification," 203
Gunst, Richard F. (*see* Carrillo-Gamboa, Olivia)
Hadi, Ali S., and Simonoff, Jeffrey S., Letter to the Editor, 373
Haitovsky, Yoel, and Rapp, Joel, "Conditional Resampling for Misclassified Multinomial Data With Applications to Sampling Inspection," 473
Hall, Peter, and Titterington, D. M.,"Edge-Preserving and Peak-Preserving Smoothing," 429
Harris, Thomas J., "Optimal Controllers for Nonsymmetric and Nonquadratic Loss Functions," 298
Hoerl, Roger W., and Palm, Andrew C., Discussion of Box, George, and Kramer, Tim, 268
Hóyland, Arnljot (*see* Doksum, Kjell A.)
Hsu, Jason C. (*see* Ruberg, Stephen J.)
Iglewicz, Boris (*see* Goldberg, Kenneth M.)
Jacroux, Mike, "A Note on the Determination and Construction of Minimal Orthogonal Main-Effect Plans," 92
Jobe, J. Marcus, and David, H. T., "Buehler Confidence Bounds for a Reliability-Maintainability Measure," 214
Johnson, Richard A. (*see* Weerahandi, Samaradasa)
Johnson, Wesley (*see* Christensen, Ronald)
Kadane, Joseph B. (*see* Crawford, Sybil L.)
Khuri, A. I., "Response Surface Models With Random Block Effects," 26
Kiiveri, H. T., "Canonical Variate Analysis of High-Dimensional Spectral Data," 321
Kramer, Tim (*see* Box, George)

Lambert, Diane, "Zero-Inflated Poisson Regression, With an Application to Defects in Manufacturing," 1
Léger, Christian, Politis, Dimitris N., and Romano, Joseph P., "Bootstrap Technology and Applications," 378
Lin, Dennis K. J., and Draper, Norman R., "Projection Properties of Plackett and Burman Designs," 423
Lorenzen, Thomas J., and Vance, Lonnie C., Letter to the Editor, 249
Lowry, Cynthia A., Woodall, William H., Champ, Charles W., and Rigdon, Steven E., "A Multivariate Exponentially Weighted Moving Average Control Chart," 46
MacGregor, John F., Discussion of Box, George, and Kramer, Tim, 273
Marr, Ray L., and Quesenberry, Charles P., Letter to the Editor, 375
McWilliams, Thomas P., Letter to the Editor, 248
Mitchell, Toby J. (*see* Welch, William J.)
Morris, Max D. (*see* Welch, William J.)
Moskowitz, Herbert, and Tang, Kwei, "Bayesian Variables Acceptance-Sampling Plans: Quadratic Loss Function and Step-Loss Function," 340
Nair, Vijayan N. (editor), "Taguchi's Parameter Design: A Panel Discussion," 127
Palm, Andrew C. (*see* Hoerl, Roger W.)
Paul, S. R., Letter to the Editor, 249
Paul, S. R., and Fung, K. Y., Letter to the Editor, 374
Pearson, Larry M. (*see* Christensen, Ronald)
Politis, Dimitris N. (*see* Léger, Christian)
Quesenberry, Charles P. (*see* Marr, Ray L.)
Rapp, Joel (*see* Haitovsky, Yoel)
Rayner, J. C. W. (*see* Best, D. J.)
Rigdon, Steven E. (*see* Lowry, Cynthia A.)
Romano, Joseph P. (*see* Léger, Christian)
Ruberg, Stephen J., and Hsu, Jason C., "Multiple Comparison Procedures for Pooling Batches in Stability Studies," 465
Sacks, Jerome (*see* Welch, William J.)
Schmoyer, Richard L., "Asymptotically Valid Prediction Intervals for Linear Models," 399
Simonoff, Jeffrey S. (*see* Hadi, Ali S.)
Small, Mitchell J. (*see* Crawford, Sybil L.)
Spiegelman, C. H. (*see* Carroll, R. J.)
Spurrier, John D., "Optimal Designs for Comparing the Variances of Several Treatments With That of a Standard Treatment," 332
Stokes, S. Lynne (*see* Greenberg, Betsy S.)
Tang, Kwei (*see* Moskowitz, Herbert)
Titterington, D. M. (*see* Hall, Peter)
Tsai, Chih-Ling, and Wu, Xizhi, "Transformation-Model Diagnostics," 197
Tucker, William T., Discussion of Box, George, and Kramer, Tim, 275 (*see also* Vander Wiel, Scott A.)
Vance, Lonnie C. (*see* Lorenzen, Thomas J.)
Vander Wiel, Scott A., Tucker, William T., Faltin, Frederick W., and Doganaksoy, Necip, "Algorithmic Statistical Process Control: Concepts and an Application," 286
Vander Wiel, Scott A., and Vardeman, Stephen B., Discussion of Box, George, and Kramer, Tim, 278
Vangel, Mark G., "New Methods for One-Sided Tolerance Limits for a One-Way Balanced Random-Effects ANOVA Model," 176
Vardeman, Stephen B. (*see* Vander Wiel, Scott A.)
Wang, J. C., and Wu, C. F. J., "Nearly Orthogonal Arrays With Mixed Levels and Small Runs," 409
Wardrop, Daniel M., and Garcia, Carlos E., Discussion of Box, George, and Kramer, Tim, 281
Weerahandi, Samaradasa, and Johnson, Richard A., "Testing Reliability in a Stress-Strength Model When K and Y are Normally Distributed," 83
Welch, William J., Buck, Robert J., Sacks, Jerome, Wynn, Henry P., Mitchell, Toby J., and Morris, Max D., "Screening, Predicting, and Computer Experiments," 15
Wong, Augustine C. M., "Inferences on the Shape Parameter of a Gamma Distribution: A Conditional Approach," 348
Woodall, William H. (*see* Lowry, Cynthia A.)
Wu, C. F. J. (*see* Wang, J. C.)
Wu, C. F. J., and Chen, Youyi, "A Graph-Aided Method for Planning Two-Level Experiments When Certain Interactions Are Important," 162
Wu, Xizhi (*see* Tsai, Chih-Ling)
Wynn, Henry P. (*see* Welch, William J.)
Yashchin, Emmanuel, "Analysis of CUSUM and Other Markov-type Control Schemes by Using Empirical Distributions," 54

BOOKS REVIEWED, BY AUTHOR

Afifi, A., and Clark, V., *Computer-Aided Multivariable Analysis*, 246
Allen, Arnold O., *Probability, Statistics, and Queueing Theory With Computer Science Applications*, 240
American Society for Quality Control, *Quality Assurance for the Chemical and Process Industries*, 102
Anderson, Erling B., *The Statistical Analysis of Categorical Data*, 364
Aoki, M., *State Space Modeling of Time Series*, 371
Armstrong, N. (editor), *Geostatistics*, 123
Arnold, J. D. (*see* Milton, J. S.)
Bain, Lee J., and Engelhardt, Max, *Statistical Analysis of Reliability and Life-Testing Models*, 486

Bakeman, Roger, and Gottman, John M., *Observing Interaction: An Introduction to Sequential Analysis*, 112
Barker, Thomas B., *Engineering Quality by Design: Interpreting the Taguchi Approach*, 230
Barnard, G., Box, G., Cox, D., Seheult, A., and Silverman, B. (editors), *Industrial Quality and Reliability*, 360
Benson, R. M. (*see* Moran, J. W.)
Bhattacharya, R. N., and Waymire, E. C., *Stochastic Processes With Applications*, 99
Bolasco, S. (*see* Coppi, R.)
Bonett, Douglas G. (*see* Woodward, J. Arthur)
Box, G. (*see* Barnard, G.)
Branham, Richard L., Jr., *Scientific Data Analysis: An Introduction to Overdetermined Systems*, 239
Brecht, Mary-Lynn (*see* Woodward, J. Arthur)
Brereton, R. (*see* Massart, D.)
Bro, P., and Levy, S. C., *Quality and Reliability Methods for Primary Batteries*, 361
Brockwell, P., and David, R., *Time Series: Theory and Methods*, 371
Bucklew, James A., *Large Deviation Techniques in Decision, Simulation and Estimation*, 120
Burger, Peter, and Gillies, Duncan, *Interactive Computer Graphics: Functional Procedural and Device-Level Methods*, 105
Carley, A., and Morgan, P., *Computation Methods in the Chemical Sciences*, 245
Caulcott, R., *Statistics in Research and Development*, 501
Chacko, George K., *Decision-Making Under Uncertainty: An Applied Statistics Approach*, 243
Christensen, R., *Log-Linear Models*, 227
Christensen, Ronald, *Linear Models for Multivariate, Time Series, and Spatial Data*, 354
Clark, V. (*see* Afifi, A.)
Clemen, Robert T., *Making Hard Decisions, an Introduction to Decision Analysis*, 365
Clements, Richard Barrett, *Handbook of Statistical Methods in Manufacturing*, 360
Cook, L. E., Jr., *No Downtime—Six Steps to Industrial Problem Solving*, 234
Coppi, R., and Bolasco, S. (editors), *Multiway Data Analysis*, 246
Cornell, John, *How to Run Mixture Experiments for Product Quality*, 370
Cornell, John A., *Experiments With Mixtures*, 104; *How to Apply Response Surface Methodology*, 359
Cox, D. (*see* Barnard, G.)
Crocker, Douglas C., *How to Use Regression Analysis in Quality Control*, 359
Crowder, M. J., and Hand, D. J., *The Analysis of Repeated Measures*, 227
Crowder, M. J., Kimber, A. C., Smith, R. L., and Sweeting, T. J., *Statistical Analyses of Reliability Data*, 485
Davis, R. (*see* Brockwell, P.)
Dessy, R. (*see* Massart, D.)
Devore, Jay L., *Probability and Statistics for Engineering and the Sciences*, 372
Diggle, Peter J., *Time Series—A Biostatistical Introduction*, 229
DiIorio Frank C., *SAS Applications Programming, a Gentle Introduction*, 366
Dobson, A. J., *An Introduction to Generalized Linear Models*, 224
Dodge, Yadolah, *Statistical Data Analysis and Inference*, 246
Dougherty, Edward R., *Probability and Statistics for Engineering, Computing, and Physical Sciences*, 241
Dovich, Robert A., *Reliability Statistics*, 118
Dowdy, Shirley, and Wearden, Stanley, *Statistics for Research*, 367
Dudewicz, Edward J. (*see* Karian, Zaven A.)
Engelhardt, Max (*see* Bain, Lee J.)
Fang, Kai-Tai, Kotz, Samuel, and Ng, Kai-Wang, *Symmetric Multivariate and Related Distributions*, 235
Farnum, Nicholas R., and Stanton, LaVerne W., *Quantitative Forecasting Methods*, 358
Fellers, Gary, *SPC for Practitioners: Special Cases and Continuous Processes*, 493
Fergenbaum, A., *Total Quality Control*, 371
Finkelstein, M., and Levin, B., *Statistics for Lawyers*, 122
Freund, R. (*see* Littell, R.)
Freund, R., and Littell, R., *SAS System for Regression*, 500
Frieden, B. R. *Probability, Statistical Optics, and Data Testing: A Problem Solving Approach*, 369
Gardiner, J. S. (*see* Montgomery, J. S.)
Gardiner, William A., *Statistical Spectral Analysis: A Nonprobabilistic Theory*, 109
Gibbons, J. D. (*see* Kendall, M.)
Gifi, Albert, *Nonlinear Multivariate Analysis*, 357
Gillies, Duncan (*see* Burger, Peter)
Gottman, John M. (*see* Bakeman, Roger)
Graupe, Daniel, *Time Series Analysis, Identification and Adaptive Filtering*, 355
Gunst, Richard F., and Mason, Robert L., *How to Construct Fractional Factorial Experiments*, 492
Haining, Robert, *Spatial Data Analysis in the Social and Environmental Sciences*, 499
Hald, Anders, *A History of Probability and Statistics and Their Applications Before 1750*, 122
Hamilton, Lawrence, C., *Statistics With STATA*, 177
Hamming, Richard W., *The Art of Probability for Scientists and Engineers*, 242

Hand, D. J. (*see* Crowder, M. J.)
Harrison, J. (*see* West, M.)
Harvey, Andrew C., *Forecasting, Structural Time Series Models and the Kalman Filter*, 496
Hastie, Trevor J., and Tibshirani, Robert J., *Generalized Additive Models*, 225
Hecht, Harry G., *Mathematics in Chemistry: An Introduction to Modern Methods*, 239
Herzberg, Paul, *How SAS Works*, 117
Hinkley, D., Reid, N., and Snell, E. J. (editors), *Statistical Theory and Modelling*, 501
Hopke, P. (*see* Massart, D.)
Hosmer, D., and Lemeshow, S., *Applied Logistic Regression*, 358
Hutchinson, T. P., and Lai, C. D., *Continuous Bivariate Distributions Emphasising Applications*, 236; *The Engineering Statistician's Guide to Continuous Bivariate Distributions*, 489
Ishikawa, Kaoru, *Introduction to Quality Control*, 494
Jambu, Michel, *Exploratory and Multivariate Data Analysis*, 489
Jobson, J. D., *Applied Multivariate Data Analysis, Volume I: Regression and Experimental Design*, 490
Johnson, L. A. (*see* Montgomery, D. C.)
Johnson, N. (*see* Kotz, S.)
Jones, Louis, and McBride, Ronald, *An Introduction to Team Approach to Problem Solving*, 103
Judd, Charles M., and McClelland, Gary H., *Data Analysis: A Model-Comparison Approach*, 107
Karian, Zaven A., and Dudewicz, Edward J., *Modern Statistical Systems and GPSS Simulation*, 366
Kaufman, L., and Rousseeuw, P. J., *Finding Groups in Data: An Introduction to Cluster Analysis*, 111
Keats, J., and Montgomery, D. (editors), *Statistical Process Control in Manufacturing*, 370
Kececioglu, Dimitri, *Reliability Engineering Handbook* (Vol. 1), 361
Kendall, M., and Gibbons, J. D., *Rank Correlation Methods*, 108
Kendall, Maurice, and Ord, J. Keith, *Time Series*, 118
Keppel, G., and Zedick, C., *Data Analysis for Research Designs*, 122
Kiemele, Mark J., and Schmidt, Stephen R., *Basic Statistics: Tools for Continuous Improvement*, 231
Kimber, A. C. (*see* Crowder, M. J.)
Klaassen, Klaas, B., and van Peppen, Jack C. L., *System Reliability: Concepts and Applications*, 234
Kotz, S., Johnson, N., and Read, C., (editors), *Encyclopedia of Statistical Sciences, Supplement Volume*, 123
Kotz, Samuel (*see* Fang, Kai-Tai)
Kutner, Michael (*see* Neter, John)
Lai, C. D. (*see* Hutchinson, T. P.)
Larsen, Richard J., and Marx, Morris L., *Statistics*, 245
Launsby, Robert G. (*see* Schmidt, Robert G.)
Lee, A. J., *U-Statistics Theory and Practice*, 364
Lee, Peter M., *Bayesian Statistics: An Introduction*, 115
Lemeshow, S. (*see* Hosmer, D.; Levy, P.)
Levin, B. (*see* Finkelstein, M.)
Levy, P., and Lemeshow, S., *Sampling of Populations: Methods and Applications*, 372
Levy, S. C. (*see* Bro, P.)
Littell, R. (*see* Freund, R.)
Littell, R., Freund, R., and Spector, P., *SAS System for Linear Models*, 500
Lochnar, Robert H., and Matar, Joseph E., *Designing for Quality, an Introduction to the Best of Taguchi and Western Methods of Statistical Experimental Design*, 100
Logothetis, N., and Wynn, H. P., *Quality Through Design*, 230
Lohmöller, Jan-Bernd, *Latent Variable Path Modeling With Partial Least Squares*, 110
Lowry, Richard, *The Architecture of Chance*, 242
Mancuso, Joseph, *Mastering Technical Writing*, 121
Mark, Howard, and Workman, Jerry, *Statistics in Spectroscopy*, 498
Marx, Morris L. (*see* Larsen, Richard J.)
Mason, Robert L. (*see* Gunst, Richard F.)
Massart, D., Brereton, R., Dessy, R., Hopke, P., Spiegelman, C., and Wegscheider, W. (editors), *Chemometrics Tutorials*, 247
Matar, Joseph E. (*see* Lochnar, Robert H.)
McBride, Ronald (*see* Jones, Louis)
McClelland, Gary H. (*see* Judd, Charles M.)
McCullagh, P., and Nelder, J. A., *Generalized Linear Models*, 224
Mendenhall, William (*see* Ott, Lyman)
Miller, A. J., *Subset Selection in Regression*, 229
Milton, J. S., (*see* Myers, R. H.)
Milton, J. S., and Arnold, J. C., *Introduction to Probability and Statistics*, 244
Moen, Ronald D., Nolan, Thomas W., and Provost, Lloyd, P., *Improving Quality Through Planned Experimentation*, 491
Montgomery, D. (*see* Keats, J.)
Montgomery, D. C., Johnson, L. A., and Gardiner, J. S., *Forecasting and Time Series Analysis*, 98
Montgomery, Douglas, C., *Design and Analysis of Experiments*, 230; *Introduction to Statistical Quality Control*, 232
Moran, J. W., Talbot, R. P., and Benson, R. M., *A Guide to Graphical Problem-Solving Processes*, 106
Morgan, P. (*see* Carley, A.)
Moura, Eduardo C., *How to Determine Sample Sizes and Estimate Failure Rate in Life Testing*, 488

Myers, R. H., and Milton, J. S., *A First Course in the Theory of Linear Statistical Models*, 228
Neapolitan, Richard E., *Probabilistic Reasoning in Expert Systems, Theory and Algorithms*, 99
Neave, H. R., *The Deming Dimension*, 104
Nelder, J. A. (*see* McCullagh, P.)
Neter, John, Wasserman, William, and Kutner, Michael, *Applied Linear Statistical Models*, 121
Ng, Kai-Wang (*see* Fang, Kai-Tai)
Noether, Gottfried E., *Introduction to Statistics: The Nonparametric Way*, 240
Nolan, Thomas W. (*see* Moen, Ronald D.)
O'Connor, Patrick D. T., *Practical Reliability Engineering*, 487
Oliver, M. A. (*see* Webster, R.)
Oliver, R., and Smith, J. (editors), *Influence Diagrams, Belief Nets, and Decision Analysis*, 114
Ord, J. Keith, (*see* Kendall, Maurice)
Ott, Lyman, and Mendenhall, William, *Understanding Statistics*, 368
Owen, Mal, *SPC and Continuous Improvement*, 100
Papoulis, Athanasios, *Probability and Statistics*, 243
Perez-Wilson, Mario, *Machine/Process Capability Study: A Five Stage Methodology for Optimizing Manufacturing Processes*, 232
Pfeiffer, Paul, *Probability for Applications*, 119
Pitard, Francis F., *Pierre Gy's Sampling Theory and Practice* (Vols. 1 and 2), 363
Provost, Lloyd P. (*see* Moen, Ronald D.)
Pyzdek, Thomas, *What Every Manager Should Know About Quality*, 495
Raheja, Dev G., *Assurance Techniques: Principles and Practices*, 233
Read, C. (*see* Kotz, S.)
Reid, N. (*see* Hinkley, D.)
Relyea, Douglas B., *Practical Application of SPC in the Wire and Cable Industry*, 101
Ripley, B. D., *Statistical Inference for Spatial Processes*, 109
Ross, Gavin J. S., *Nonlinear Estimation*, 108, 356
Ross, Sheldon M., *A Course in Simulation*, 236
Rousseeuw, P. J. (*see* Kaufman, L.)
Sanders, Donald H., *Statistics—A Fresh Approach*, 244
Schmidt, Stephen R. (*see* Kiemele, Mark J.)
Schmidt, Stephen R., and Launsby, Robert G., *Understanding Industrial Designed Experiments*, 492
Seheult, A. (*see* Barnard, G.)
Shapiro, Samuei S., *How to Test Normality and Other Distributional Assumptions*, 359
Silverman, B. (*see* Barnard, G.)
Simpson, H. R. (*see* Snell, E. J.)
Smith, J. (*see* Oliver, R.)
Smith, R. L. (*see* Crowder, M. J.)
Snell, E. J. (*see* Hinkley, D.)
Snell, E. J., and Simpson, H. R., *Applied Statistics: A Handbook of GENSTAT Analyses*, 499
Spector, P. (*see* Littell, R.)
Spiegelman, C. (*see* Massart, D.)
Stanton, LaVerne W. (*see* Farnum, Nicholas R.)
Subrahmaniam, Kathleen, *A Primer in Probability*, 369
Sweeting, T. J. (*see* Crowder, M. J.)
Talbot, R. P. (*see* Moran, J. W.)
Tibshirani, Robert J. (*see* Hastie, Trevor J.)
Tierney, Luke, *Lisp-Stat, an Object-Oriented Environment for Statistical Computing and Dynamic Graphics*, 238
Tufte, Edward R., *Envisioning Information*, 106
Tunner, Joseph R., *A Quality Technology Primer for Managers*, 362
Van Peppen, Jack C. L. (*see* Klaassen, Klaas B.)
Wahba, Grace, *Spline Models for Observational Data*, 113
Wasserman, William (*see* Neter, John)
Waymire, E. C. (*see* Bhattacharya, R. N.)
Wearden, Stanley (*see* Dowdy, Shirley)
Webster, R., and Oliver, M. A., *Statistical Methods in Soil and Land Resource Survey*, 497
Wegscheider, W. (*see* Massart, D.)
West, M., and Harrison, J., *Bayesian Forecasting and Dynamic Models*, 115
Wheeler, Donald J., *Understanding Industrial Experimentation*, 370
Woodward, J. Arthur, Bonett, Douglas G., and Brecht, Mary-Lynn, *Introduction to Linear Models and Experimental Design*, 354
Workman, Jerry (*see* Mark, Howard)
Wynn, H. P. (*see* Logothetis, N.)
Zedick, C. (*see* Keppel, G.)

BOOK REVIEWERS

Abeshouse, David J. (*see* Maryak, John L.)
Adams, James A., 362
Ammann, Larry P., 238
Angus, John E., 496
Aragón, Jorge, 242
Armitage, Stan J., 368
Barker, Lawrence, 485
Baxter, Lawrence A., 240
Bayne, Charles K., 110
Berk, Robert H., 112
Berliner, L. Mark, 115
Bieger, Charles D., 117
Bilonick, Richard, 363
Blazek, Linda W., 105
Boggs, Brady, 234
Booth, David E., 118
Bossert, James L., 494
Brooks, Daniel G., 239
Brugger, Richard M., 360, 492
Bryson, Maurice C., 486

Carlson, Richard R., 495
Chang, Phil T., 491
Chen, Chung, 358
Cohen, Jonathan, 497
Coleman, David, 359
Cucchiara, Andrew, 358
Czitrom, Veronica, 104
De Veaux, Richard D., 225
Diegert, Kathleen, 360
Driscoll, Michael F., 499
Edgeman, Rick L., 230
Emptage, Michael, 224
Farnsworth, David L., 240
Freitas, Stephen A., 244
Galway, Lionel, 113
Gill, P. S., 354
Goodall, Colin, 357
Goodman, Jay H., 498
Gotway, Carol A., 499
Govindarajulu, Z., 108
Groggel, David J., 243
Guttorp, Peter, 242
Habibullah, Mohamed, 227
Hadi, Ali S., 111
Hapeman, David E., 364
Harris, Thomas, 355
Heydorn, Richard P., 487
Hulting, Fred L., 488
Hwan, Marilyn, 230
Inglis, James, 367
Jensen, Karen L., 101
Jones, P. W., 99
Kianifard, Farid, 228, 490
Kirmani, S. N. U. A., 99
Koehler, James R., 109
Kotlovker, Debbi, 245
Kramer, Tim, 493
Kushary, Debashis, 108
LaLonde, Steven M., 366
Lawrence, Kenneth D., 366
Leigh, Stefan D., 364
Lewis, Richard A., 102
Lindstrom, Mary J., 227
Liu, Shin Ta, 243, 365
Loh, Wei-Yan, 235
Lordo, Robert A., 236
Maryak, John L., and Abeshouse, David, 369
Morganstein, David, 103
Nemeth, Margaret A., 231
Niple, Edward R., 354
Notz, William I., 236, 489
Pankratz, Peter C., 492
Parmigiani, Giovanni, 120
Percival, Donald, B., 109
Pfahler, Lori, 104
Pitts, Karen A., 106
Propst, Annabeth L., 100, 359
Rabinowitz, Larry, 369
Rigdon, Steven E., 118, 239
Sandry, Thomas D., 356
Sauter, Roger M., 232
Schaefer, Robert L., 229
Schneider, Helmut, 361
Schuenemeyer, John H., 224
Scott, Douglas M., 106
Shanmugam, Ramalingam, 233
Srinivasan, Symala, 230
Stone, Ricardo R., 232
Terrell, George R., 114
Thomson, Steve, 117
Tsokos, Chris P., 229
VanBrackle, Lewis N., 119
Vining, Geoff, 107
Waller, Ray A., 241
Walters, Sherry K., 361
Westfall, Peter H., 115
Wolkan, Joseph A., 244
Woodall, William H., 100
Zhang, Nien Fan, 98
Ziegel, Eric R., 121, 245, 370, 500